

03/04

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250227US-2X DIV		SERIAL NO. New DIV. Appln.	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shinji IINO, et al.			
				FILING DATE Herewith		GROUP 2829	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Me	AA	5,258,654	11/02/93	P.S. Roberts, et al.			
	AB	5,773,987	06/30/98	T.T. Montoya			
	AC	5,523,633	06/04/96	N. Imaizumi, et al.			
	AD	4,851,707	07/25/89	D.S. Lindsay			
	AE	4,477,774	10/1984	Revirieux, Michel			
	AF	6,057,694	05/2000	Matsudo			
	AG	5,936,419	08/1999	Chen			
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
Me	AO	11-242062	09/07/99	Japan (with English Abstract)			x
	AP	JP 64-048038	02/1989	Japan			
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
Me	AW	Mark Bailey, et al. "A Micromachined Array Probe Card-Characterization" IEEE Transactions on Components, Packaging, and Manufacturing Technology-Part B, Vol. 18, No. 1, February, 1995 pgs. 184-191					
	AX						
	AY						
	AZ						
Examiner					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 10/21/04		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							